

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1942952	semiconductor or integrated adj circuit or dut or device near under near test\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 15:21
L2	121	1 and time near interpolators	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 15:21
L3	24	2 and digital near filter	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 15:22
L4	20	3 and select\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 15:22